

FIG.1

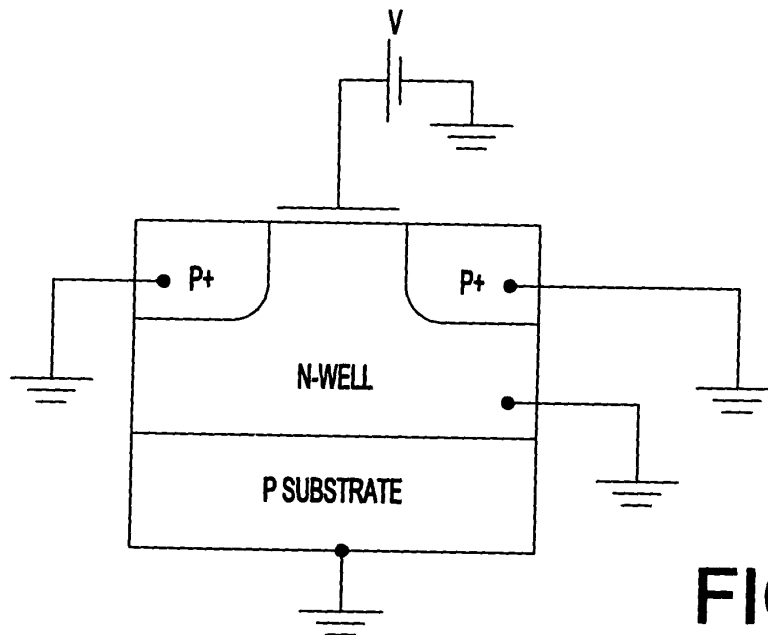


FIG.2

202130-5625007

20250520 10050400

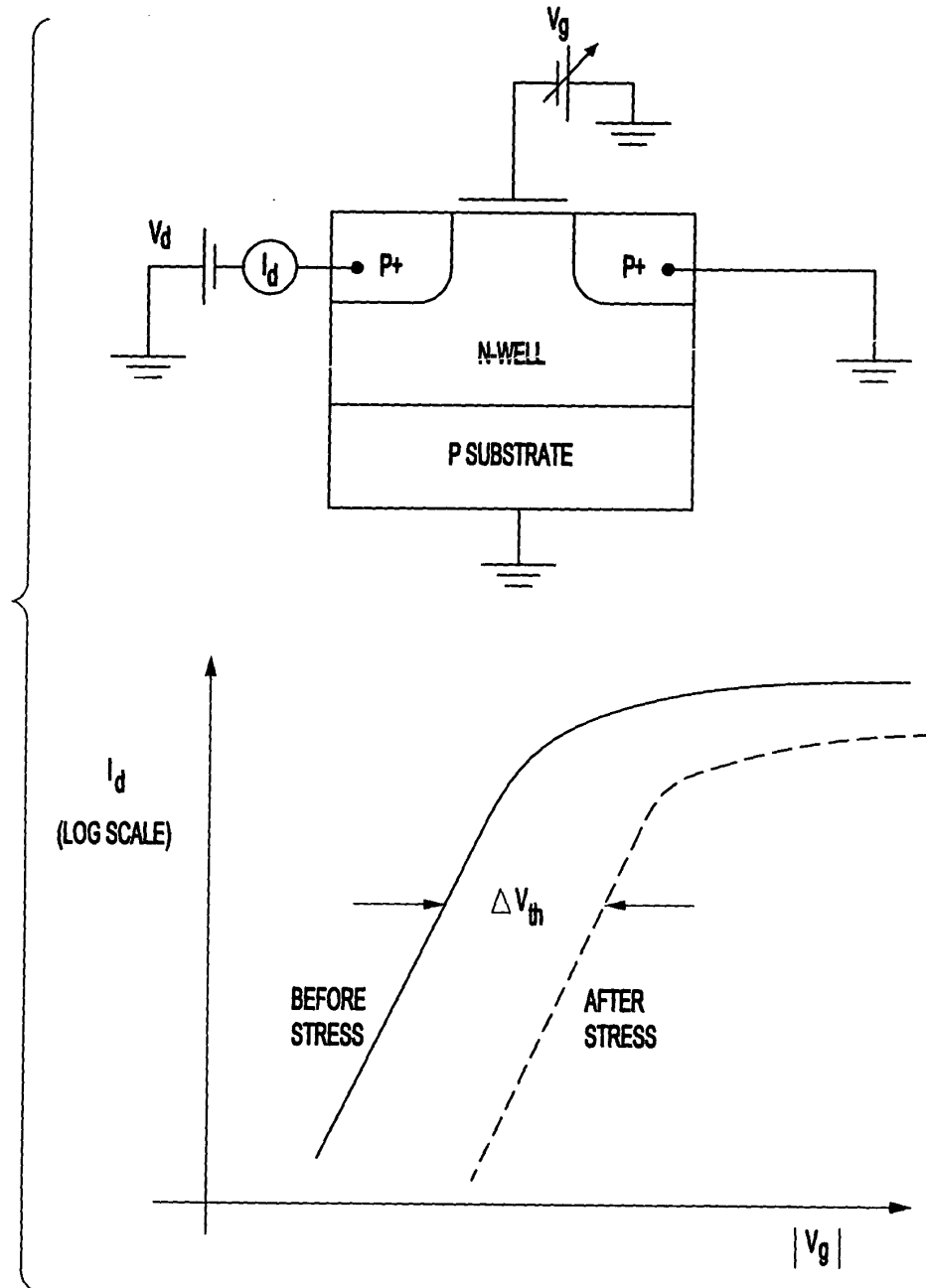
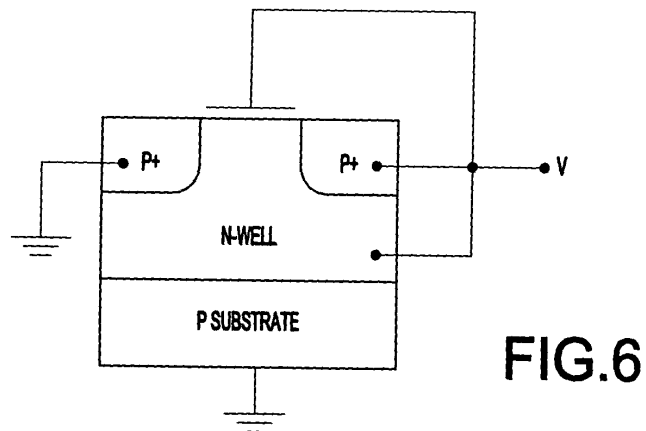
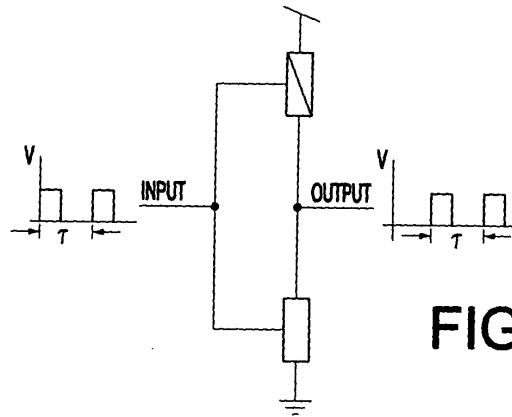
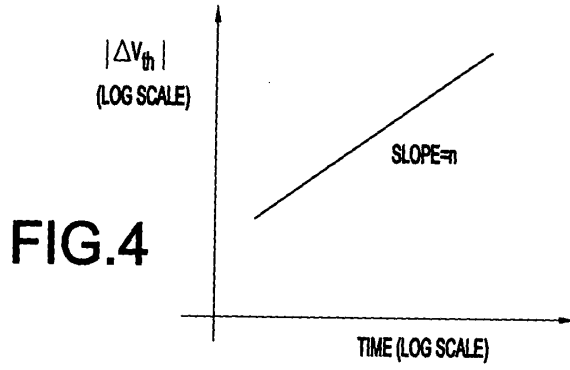


FIG.3



10053205-051202  
20190522

2021501562E9001

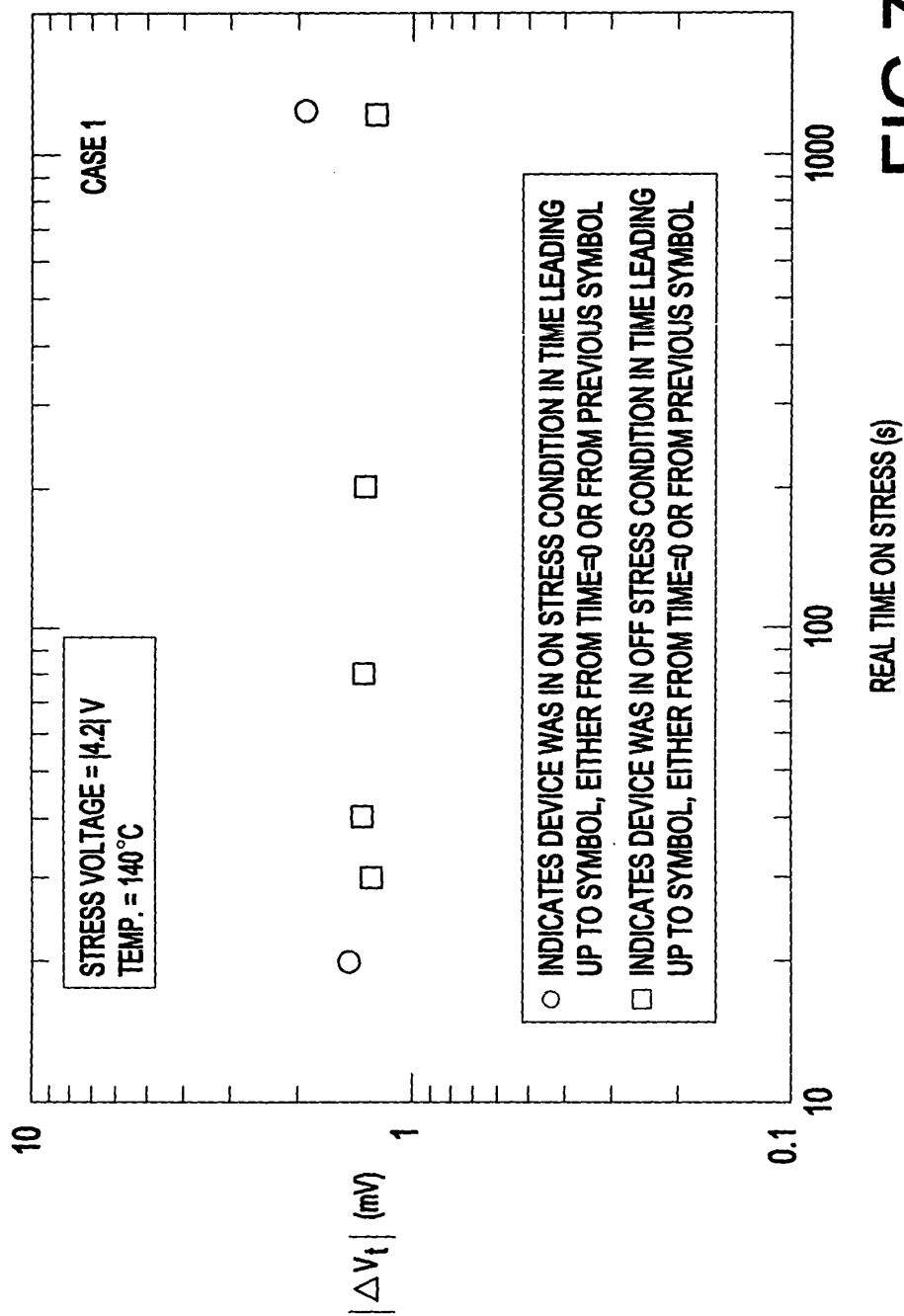


FIG.7A

20250720 14:21:50

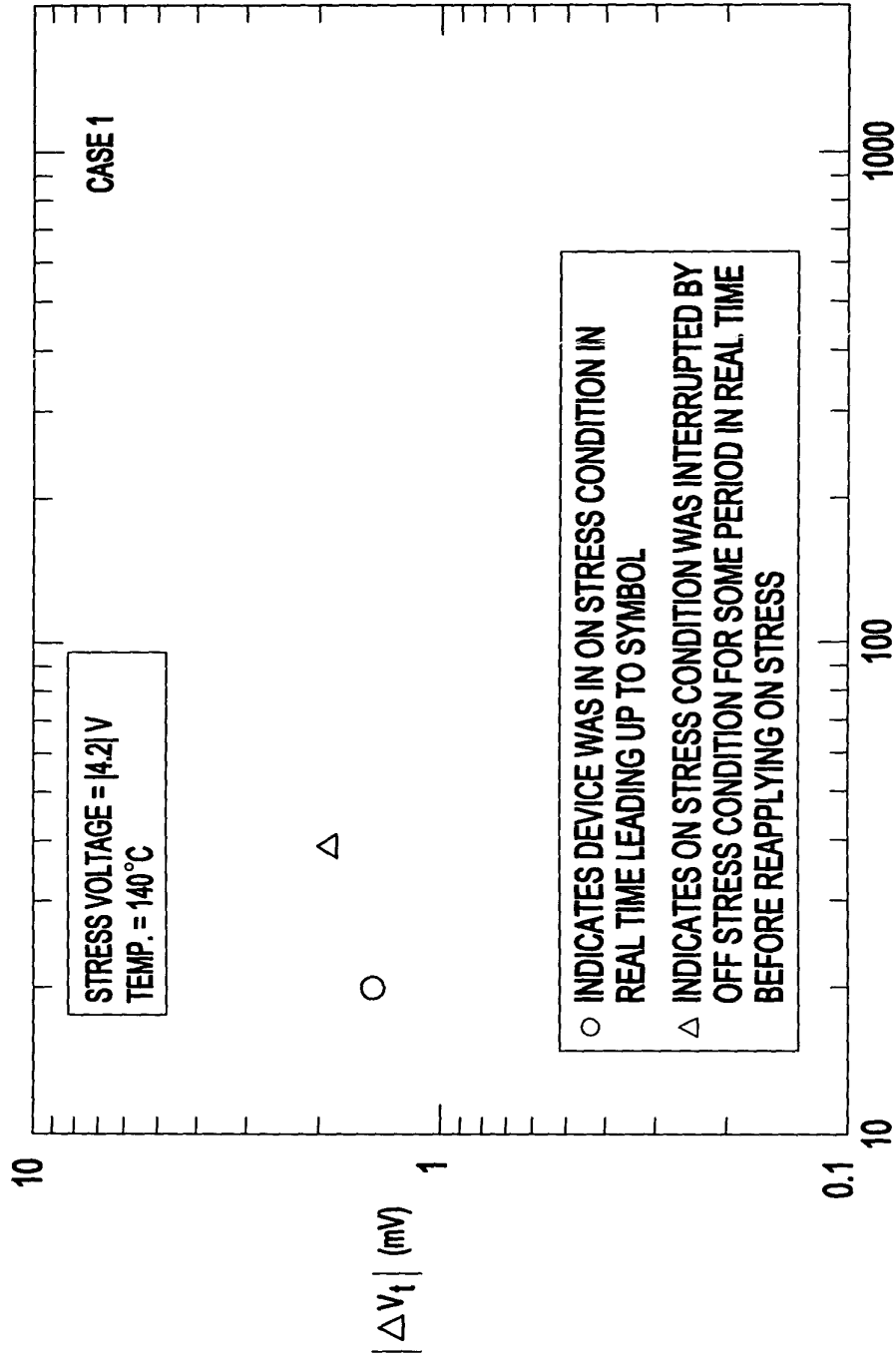


FIG.7B

60250-9625001

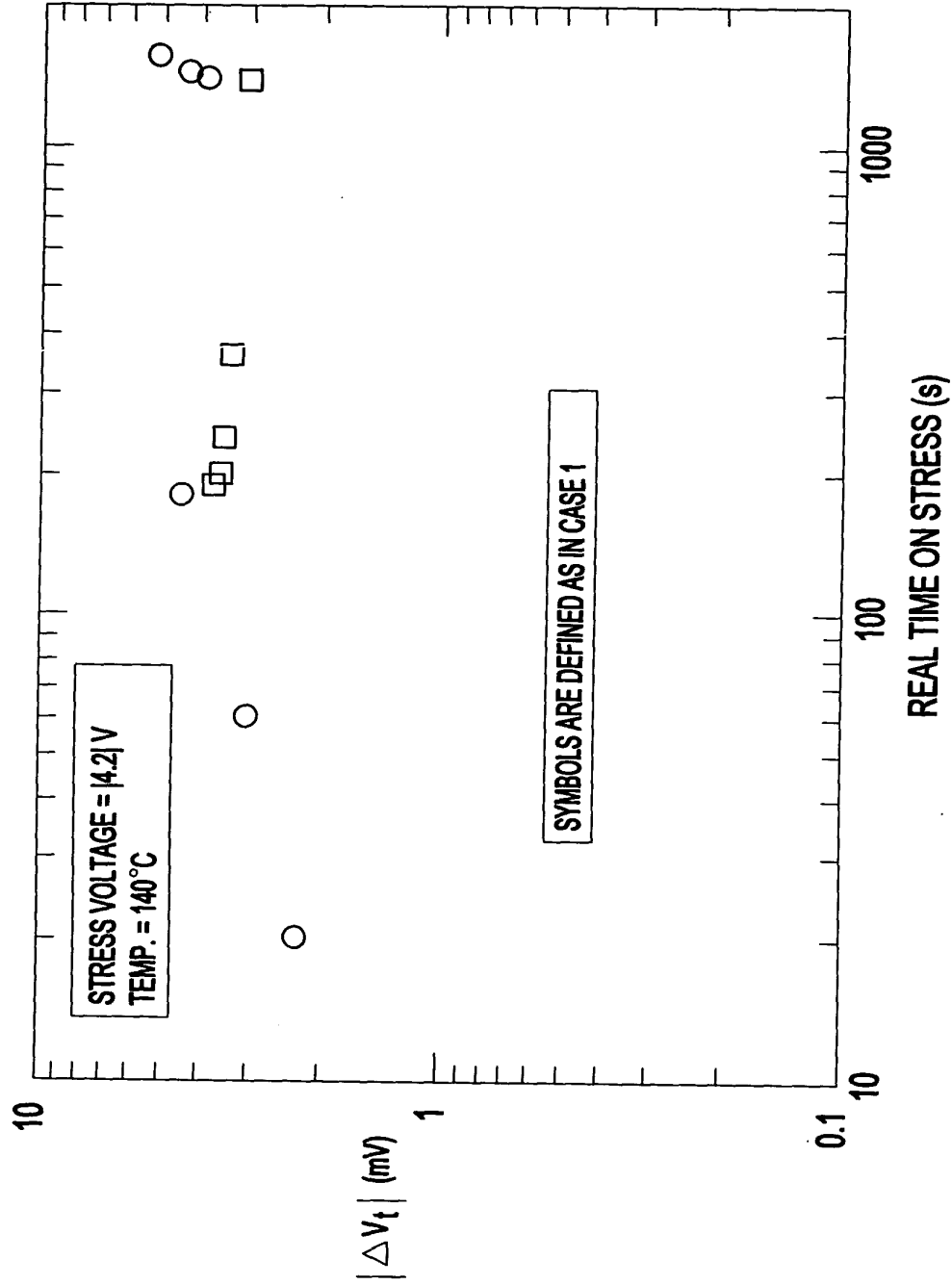


FIG.8A

202T90-56263001

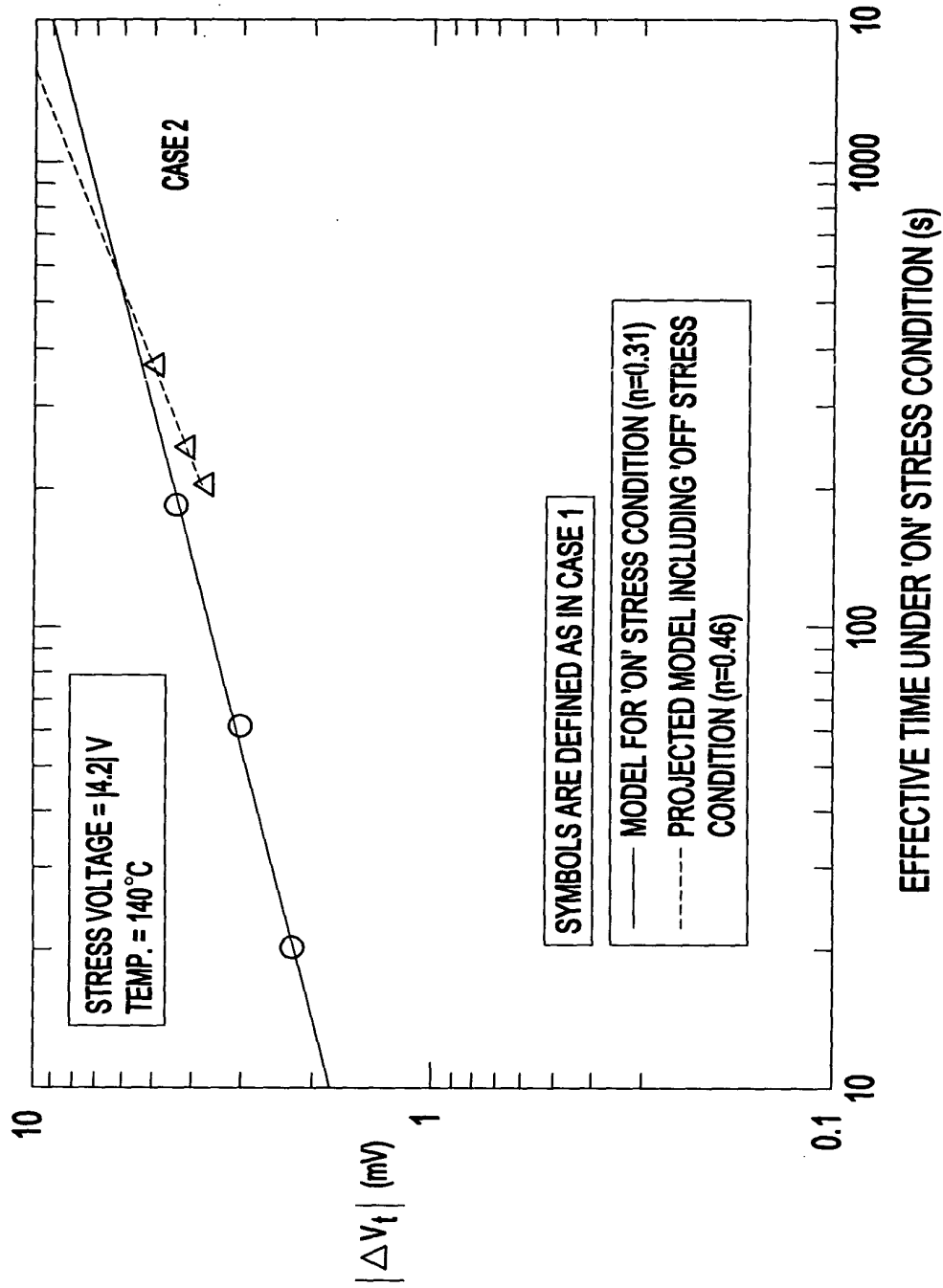


FIG.8B

202190-5629001

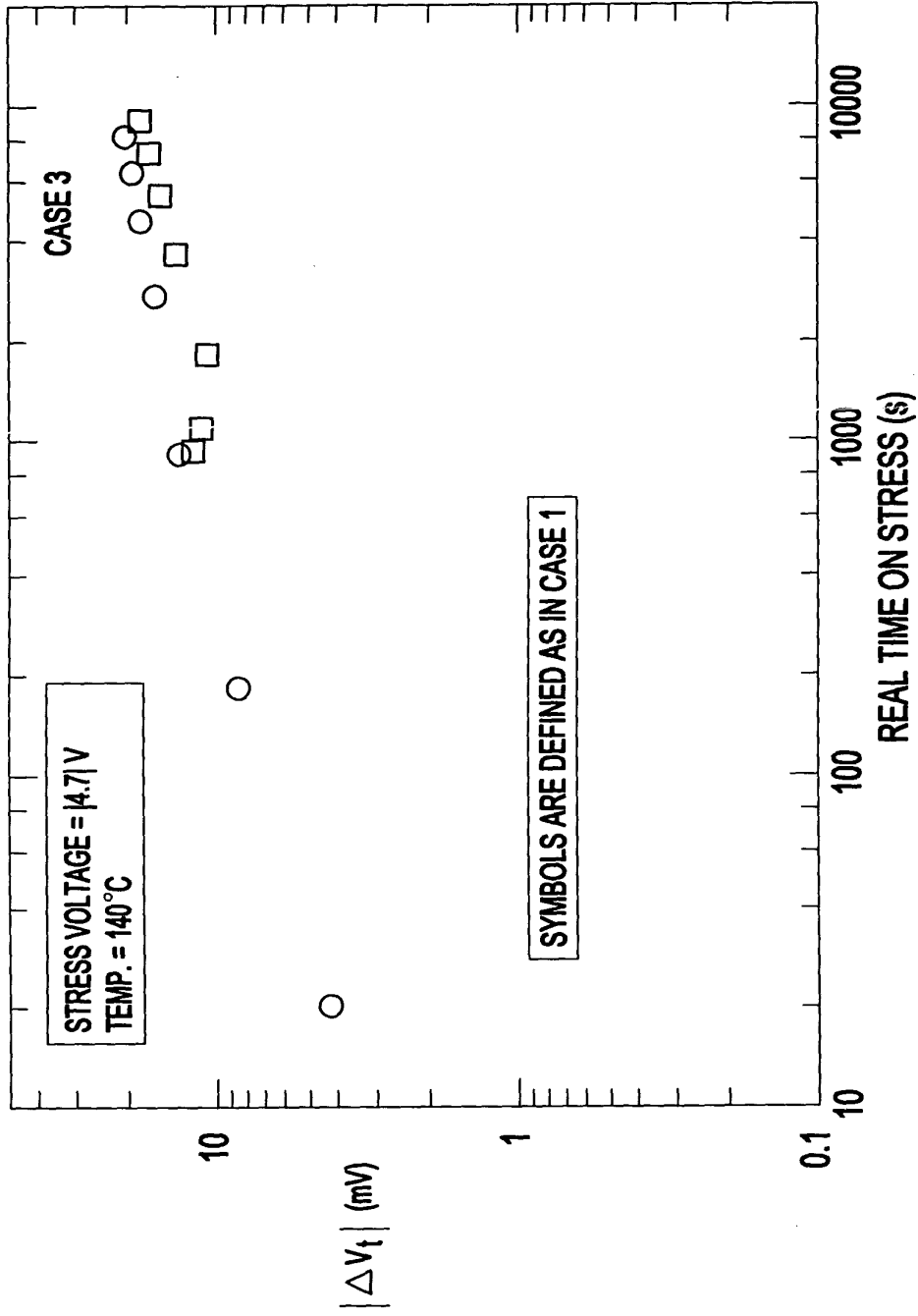


FIG.9A



2024 90 562E9001

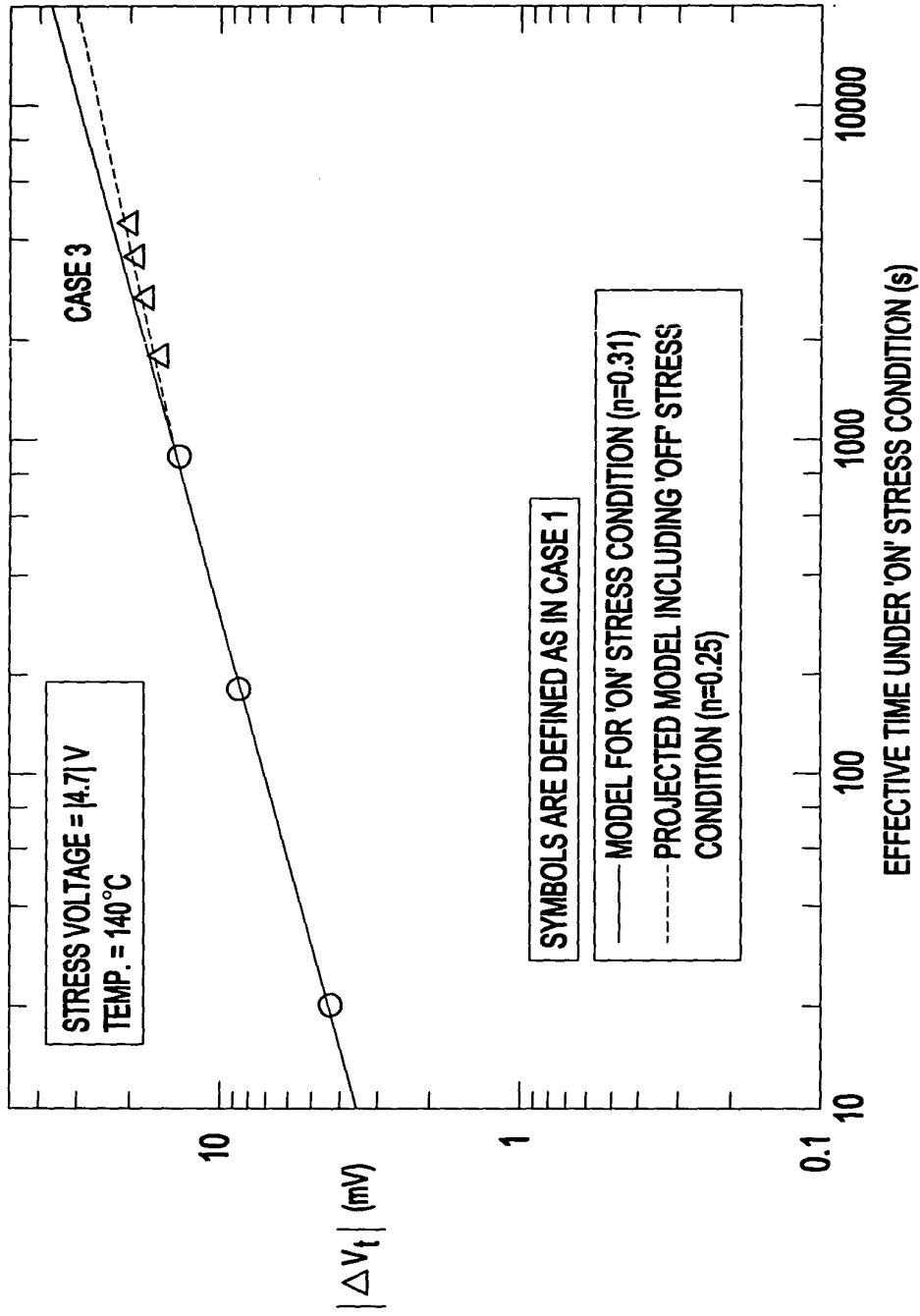


FIG.9B

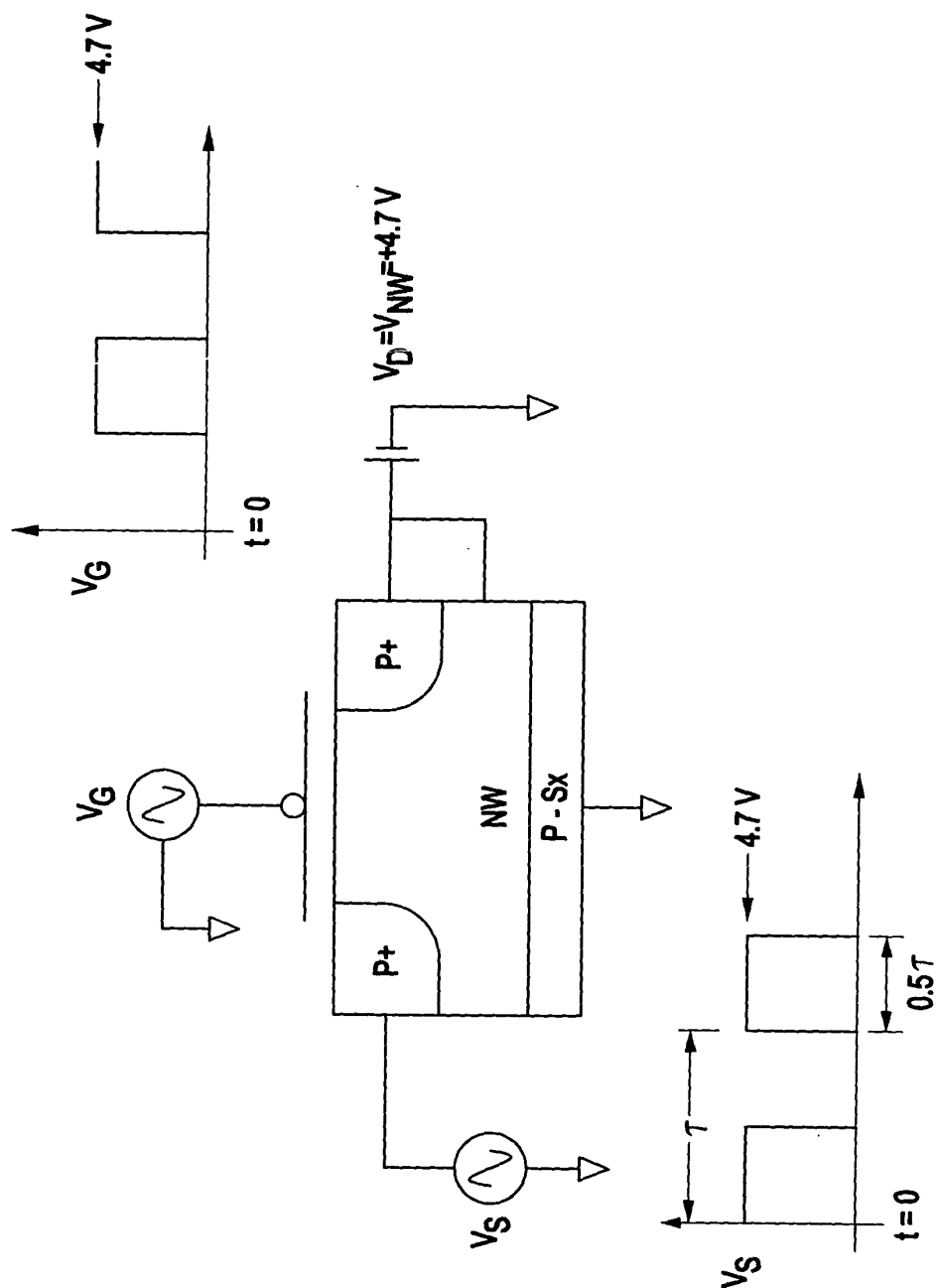


FIG.10

202150-56225007

11/20  
BUR920010127U51

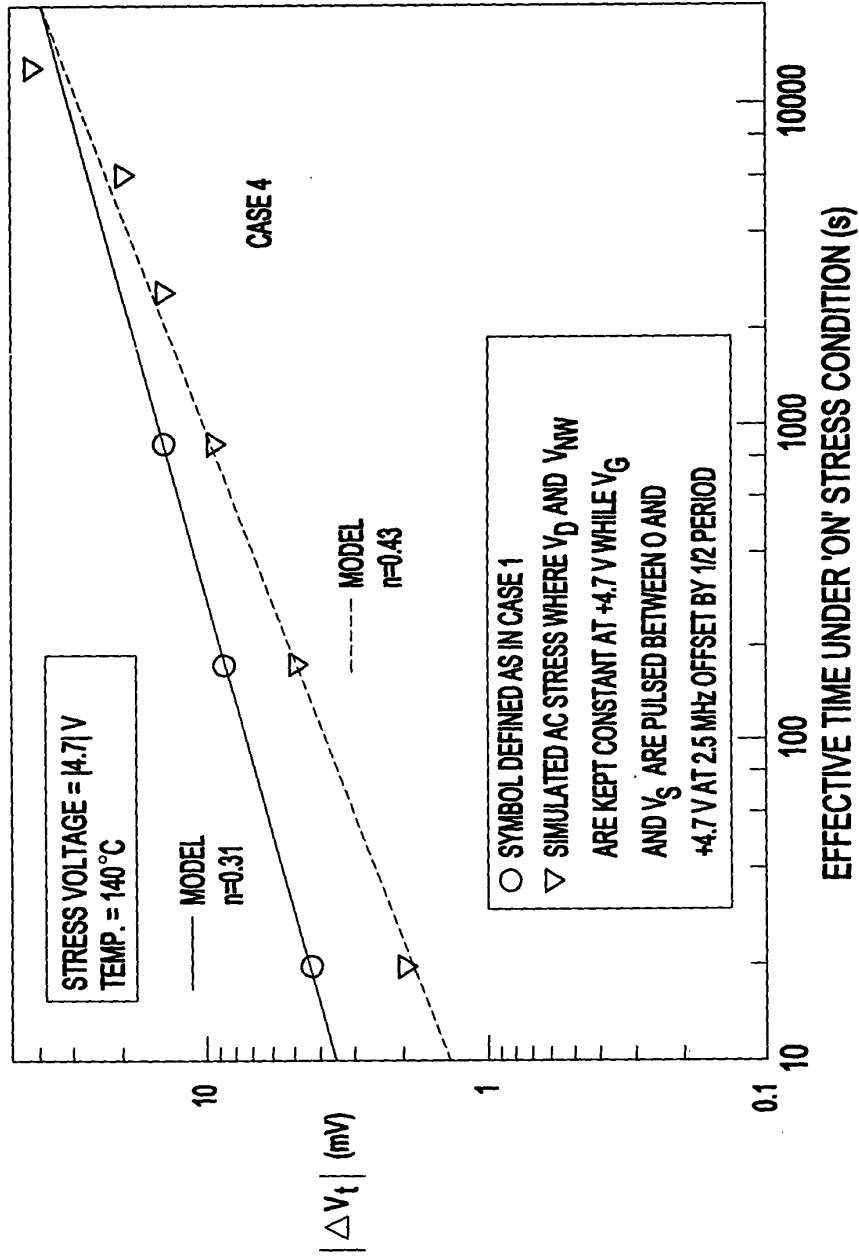
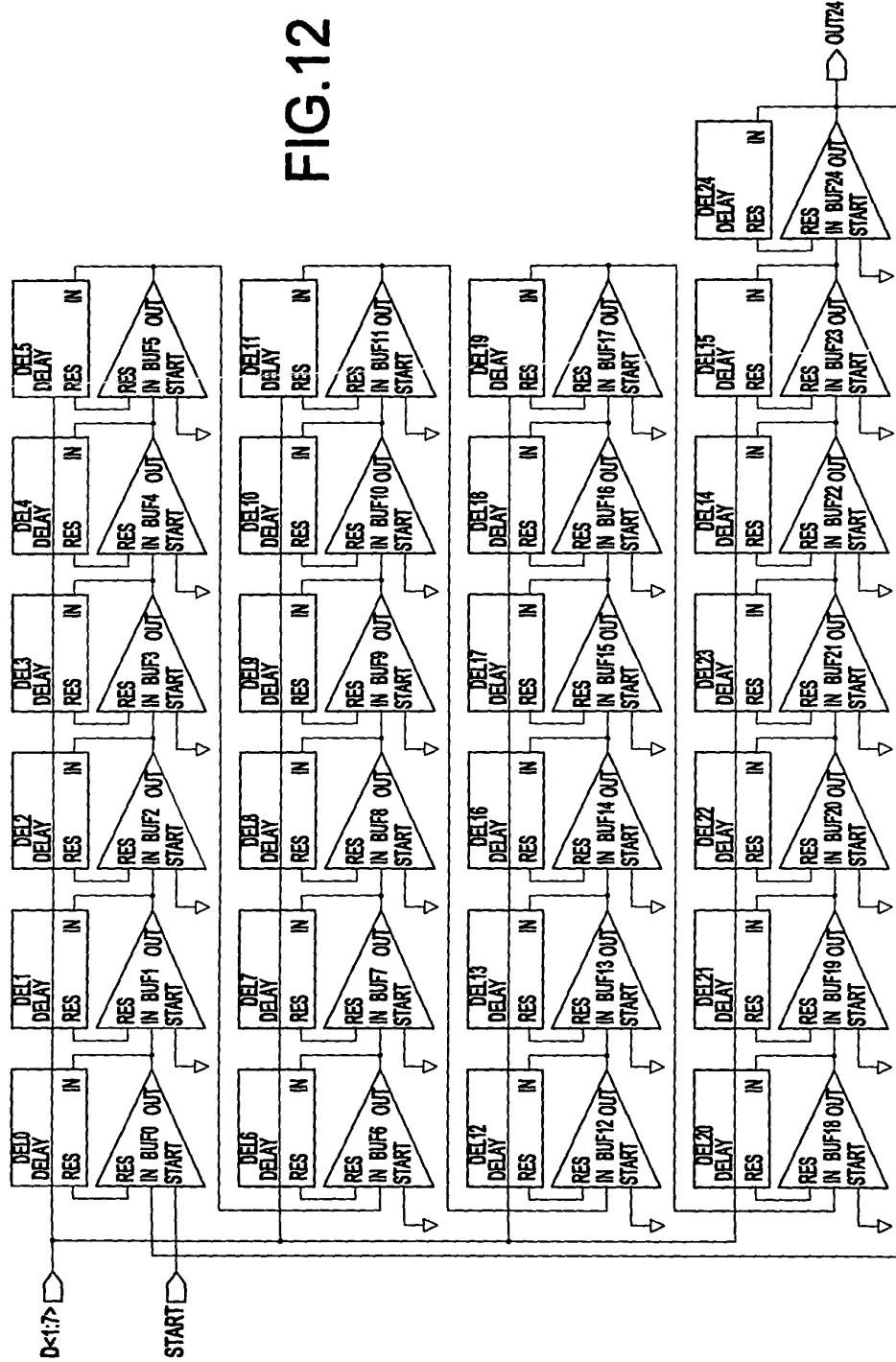


FIG.11

202150-50225001

FIG.12



202150-5625001

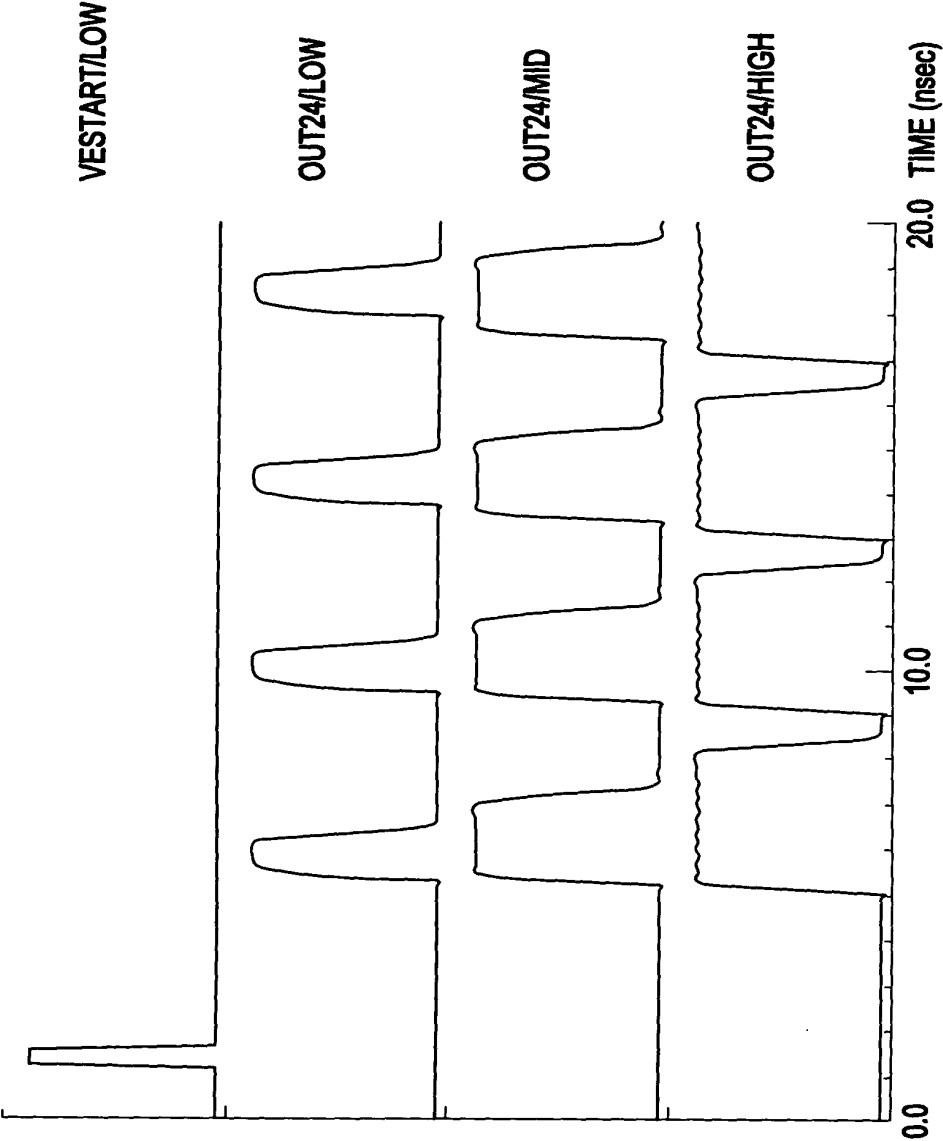


FIG.13

202150-562E9007

# DVTSBUF PULSE PROPAGATOR STRUCTURE

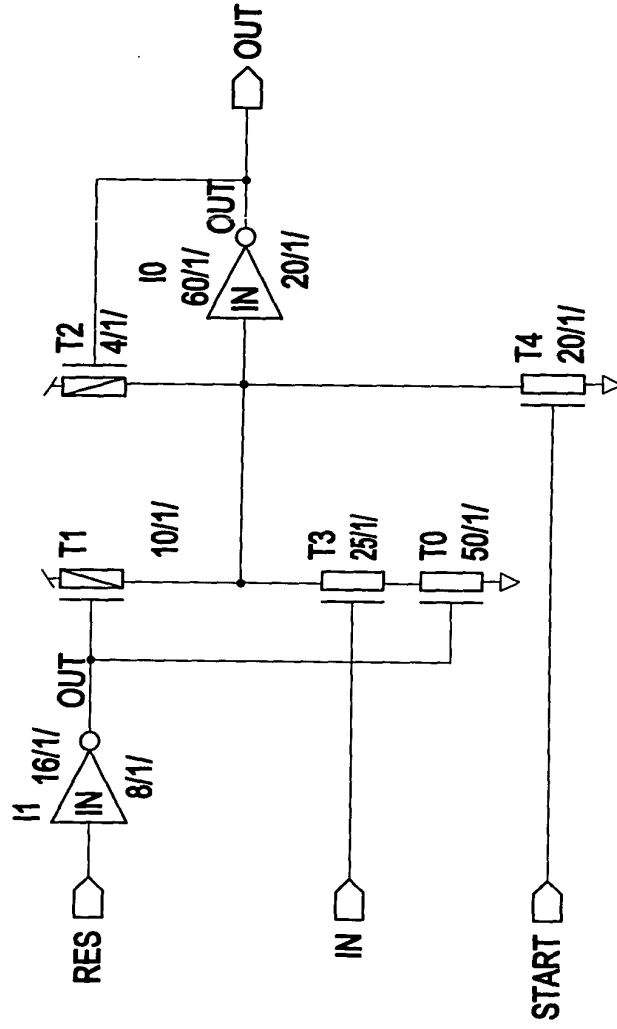


FIG.14

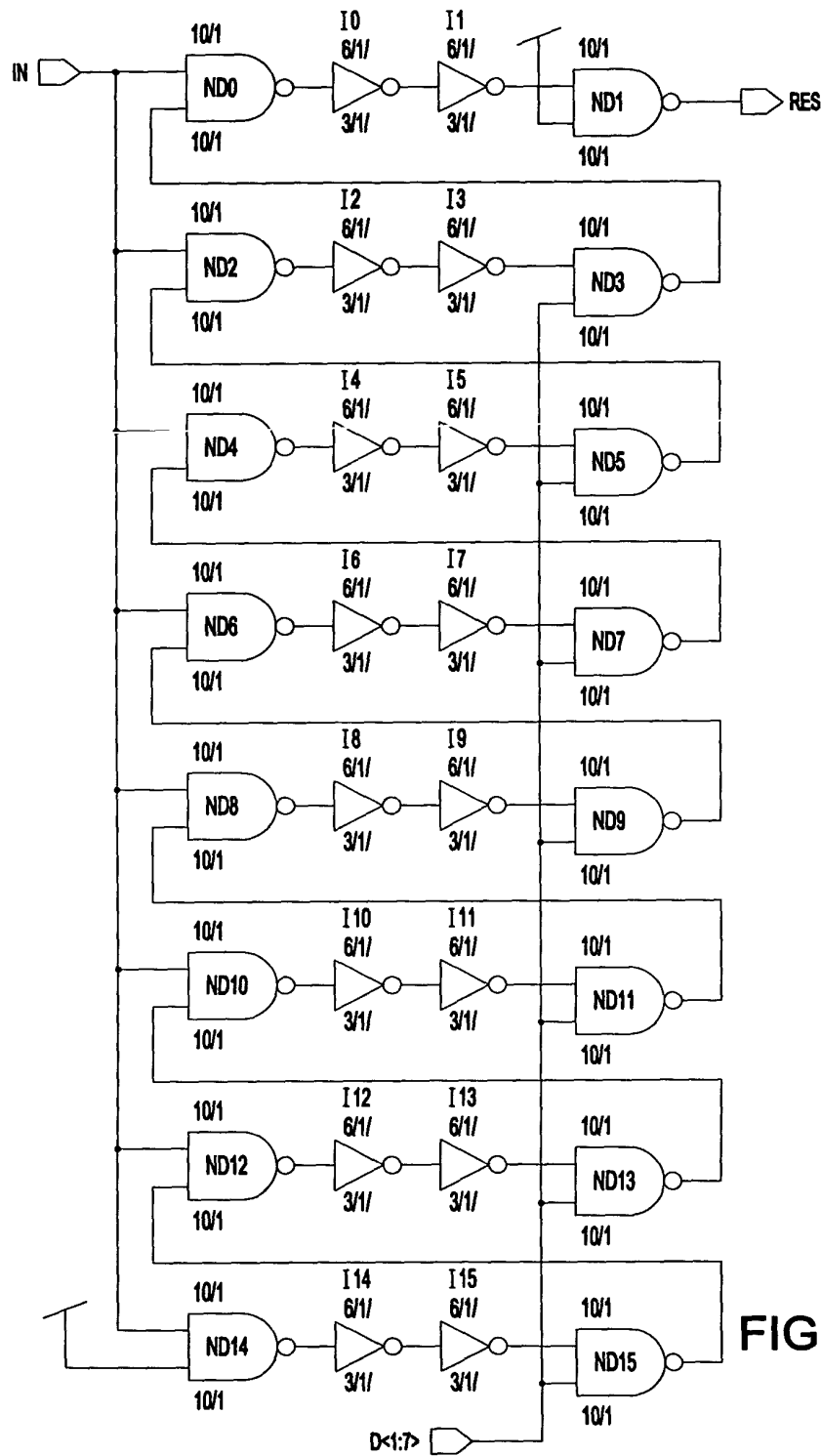


FIG.15

INPUT	FREE RUN	AC STRESS	DC STRESS
SOURCE	VDD	VDD	VDD/GND
GATE	GND	"A.C."	VDD/GND
VPP	VPP	VPP	VPP
bSTRESS1	VDD	VDD	GND
IN	"A.C."	GND	GND
DRAIN	VDD	VDD	VDD/GND
bSTRESS2	VPP	GND	GND

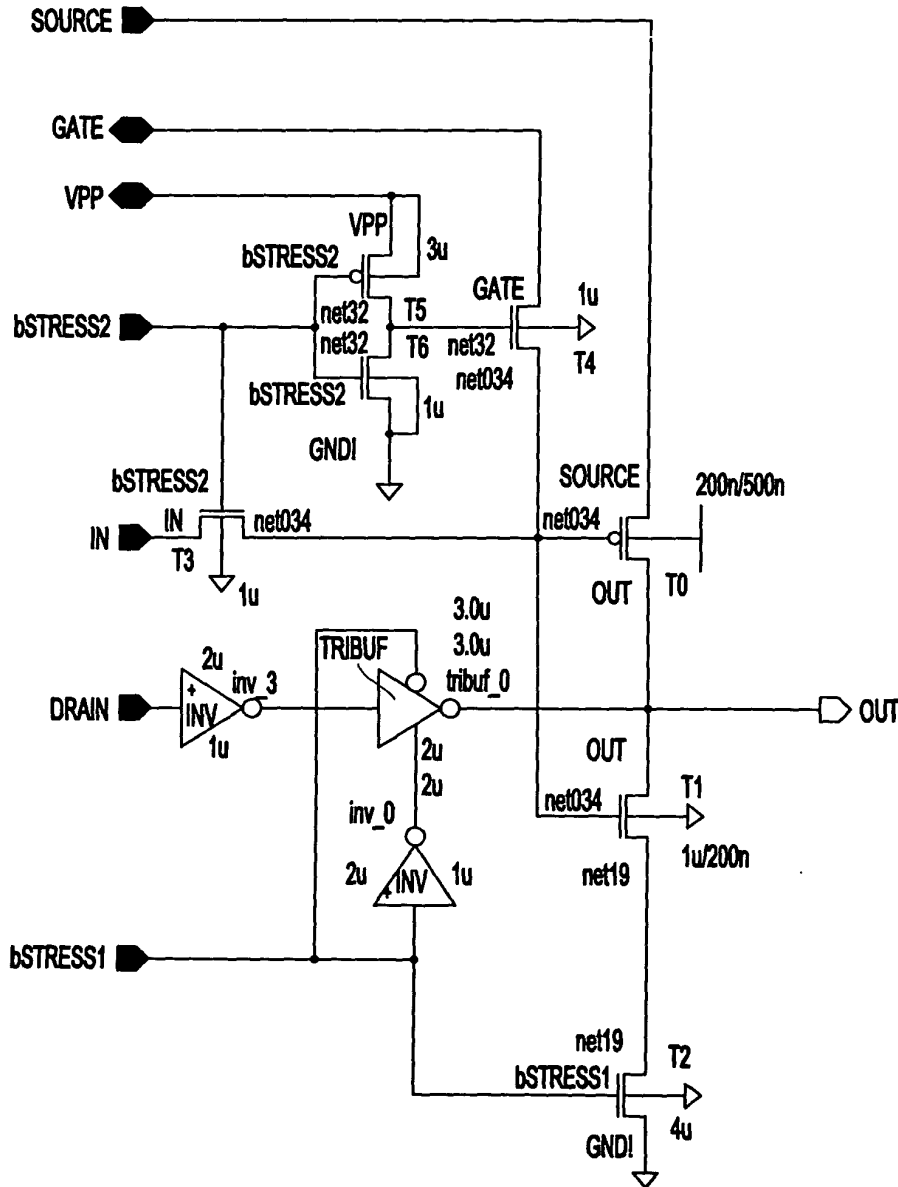
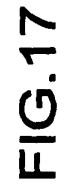


FIG.16

2025-06-10 10:06:29





202190 50229001

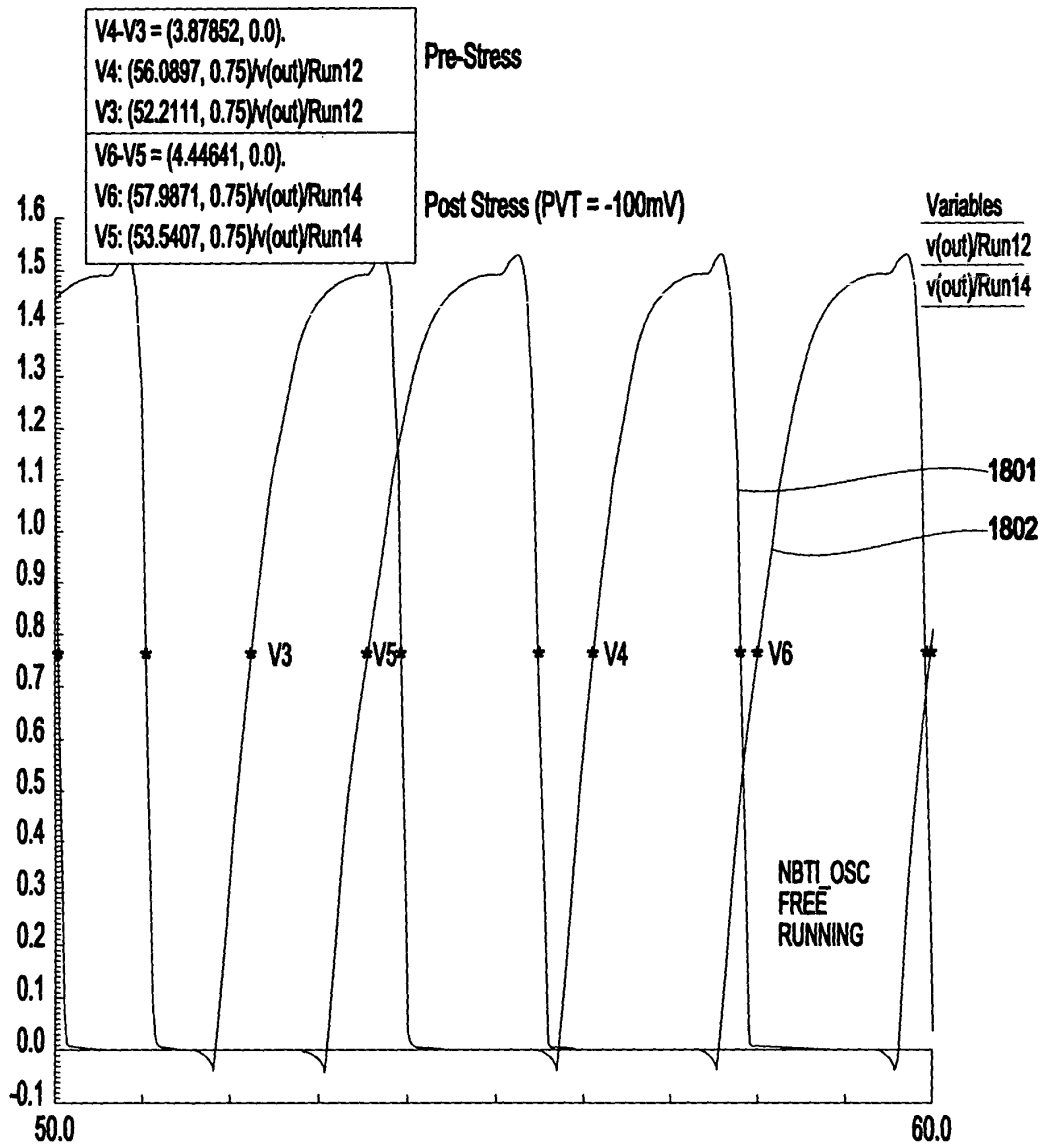
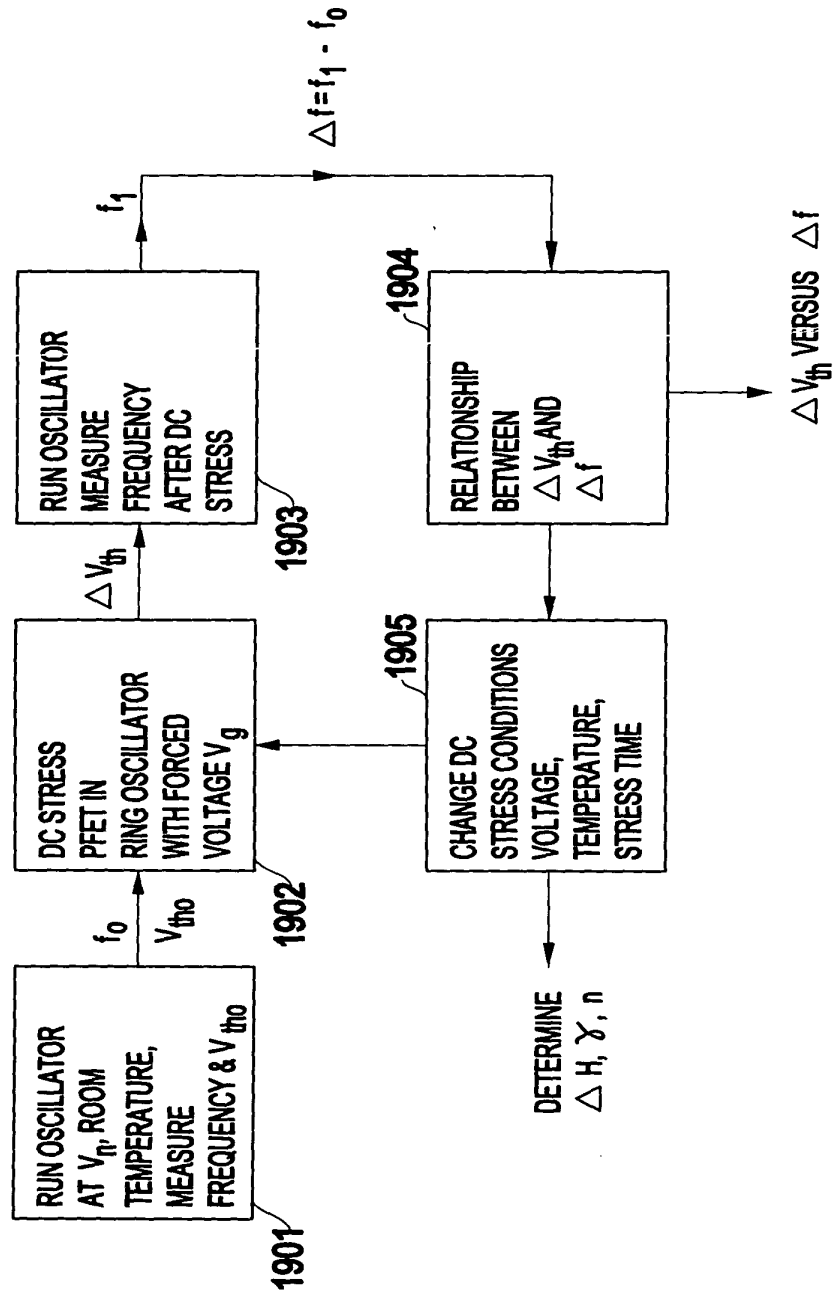


FIG.18

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# APPLICATION OF PFET DC STRESS IN RING OSCILLATOR AND DETERMINING DEGRADATION CONSTANTS



2002F50-562E9001

FIG.20

